

RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS1000M-25	Feb-96	9552 E2	OMEDATA	DD525039AFA	1.2μ NITRIDE	08 PDIP

STRESS/JOB NO.

READPOINT (Sample Size/No. of Fails)

Infant / High Voltage Life 125°C, 7.0 V. P-16943, P-16983	<u>48 Hr</u> 231/1	<u>336 Hr</u> 77/0	<u>1KHr</u> 77/0	<u>*Failure Rate</u> 66 Fits
	F1			

*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle -55°C to +125°C P-16984	<u>300 ~</u> 38/0	<u>1K ~</u> 38/0	<u>Cum %</u> 0.0%

Biased Moisture 85°C/85% RH, 5.5 V. P-16985	<u>274 Hr</u> 77/0	<u>959 Hr</u> 77/0	<u>Cum %</u> 0.0%

Autoclave 121°C/100% RH, 2 Atmos P-16986	<u>96 Hr</u> 38/0	<u>Cum %</u> 0.0%

Failure Mode

F1: Icc